			(A ^K
	Application No.	Applicant(s)	O , 1
Notice of Allematics	09/873,218	MATSUMOTO, KENJI	
Notice of Allowability	Examin r	Art Unit	
	Tuan N Nguyen	2828	
The MAILING DATE of this communication appe All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this ap or other appropriate communication GHTS. This application is subject t	pplication. If not include n will be mailed in due	ded e course. THIS
1. This communication is responsive to 12/10/2003.			•
2. ☑ The allowed claim(s) is/are <u>1-5</u> .			
3. A The drawings filed on 10 December 2003 are accepted by	the Examiner.		
 Acknowledgment is made of a claim for foreign priority un a)	der 35 U.S.C. § 119(a)-(d) or (f).		
1. Certified copies of the priority documents have	been received.		
2. Certified copies of the priority documents have	been received in Application No		
3. Copies of the certified copies of the priority doc	cuments have been received in this	national stage applica	ation from the
International Bureau (PCT Rule 17.2(a)).			
* Certified copies not received:			
Applicant has THREE MONTHS FROM THE "MAILING DATE" on noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.	of this communication to file a reply ENT of this application.	complying with the re	equirements
 A SUBSTITUTE OATH OR DECLARATION must be submi INFORMAL PATENT APPLICATION (PTO-152) which give CORRECTED DRAWINGS (as "replacement sheets") must 	s reason(s) why the oath or declara	A'S AMENDMENT or I ation is deficient.	NOTICE OF
(a) ☐ including changes required by the Notice of Draftsperso		049) ottochod	•
1) hereto or 2) to Paper No./Mail Date	ons ratent brawing Neview (F10-	-940) attached	
(b) ☐ including changes required by the attached Examiner's Paper No./Mail Date	Amendment / Comment or in the C	Office action of	
Identifying indicia such as the application number (see 37 CFR 1. each sheet. Replacement sheet(s) should be labeled as such in the	84(c)) should be written on the drawine header according to 37 CFR 1.121(ngs in the front (not th	e back) f
 DEPOSIT OF and/or INFORMATION about the depose attached Examiner's comment regarding REQUIREMENT F 	sit of BIOLOGICAL MATERIAL r FOR THE DEPOSIT OF BIOLOGIC	must be submitted. AL MATERIAL.	Note the
			3
	•		
Attachment(s) 1. ☐ Notice of References Cited (PTO-892)	E Notice of Informal E	otont Analisation (DT	0.450
2. ☐ Notice of References Cited (PTO-692) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)	5. Notice of Informal P		O-152)
2. Involce of Dranperson's Patent Drawing Review (P10-946)	6. ☐ Interview Summary Paper No./Mail Da		
 Information Disclosure Statements (PTO-1449 or PTO/SB/08 Paper No./Mail Date 	8), 7. Examiner's Amendr	ment/Comment	
4. Examiner's Comment Regarding Requirement for Deposit	8. Examiner's Stateme	ent of Reasons for Alle	owance
of Biological Material Don Wong	9.		· .
Supervisory Patent Examiner Technology Center 2800			er sarar er er er e
Xm 8 lange			
U.S. Patent and Trademark Office PTOL-37 (Rev. 1-04)	tice of Allowability	Part of Paper No	o./Mail Date 050704

Application/Control Number: 09/873,218

Art Unit: 2828

DETAIL ACTION

Response to Amendment

1. In respond to applicant's amendment filed 12/10/2003, the substitute formal drawings Figs. 1A, 7A, 13A, 18A, 18B, 19-22 are accepted.

REASON FOR ALLOWANCE

Allowable Subject Matter

2. The following is an examiner's statement of reasons for allowance - Applicant's response filed on 12/10/2003 has been considered, with respect to claims 1-4, the references of the record fail to teach or suggest:

A method of fabricating a semiconductor laser having a structure in which an equivalent refractive index of two portions disposed apart from each other is higher than that of adjacent portions to these portions in a direction perpendicular to a waveguide direction as well as in parallel with an activation layer, comprising the steps of: forming said activation layer and a plurality of layers in parallel with said activation layer; forming a first groove penetrating through at least some of said plurality of layers; selectively etching a specified layer among at least some of said plurality of layers through which said first groove penetrates, said etching extending from both sides of the first groove to a predetermined position in said specified layer, thus forming a pair of second grooves; and filling up said second grooves with a material having a refractive index higher than that of said specified layer, thus forming two portions having said high equivalent refractive index.

Application/Control Number: 09/873,218

Art Unit: 2828

3.

Page 3

payment of the issue fee and, to avoid processing delays, should preferably accompany the issue

Any comments considered necessary by applicant must be submitted no later than the

fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for

Allowance."

Communication Information

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tuan N Nguyen whose telephone number is (571) 272-1948. The

examiner can normally be reached on M-F: 7:30 - 4:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Don Wong can be reached on (571) 272-1834. The fax phone numbers for the

organization where this application or proceeding is assigned are (703) 872-9318 for regular

communications and (703) 872-9319 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding

should be directed to the receptionist whose telephone number is (703) 306-3329.

Tuan N. Nguyen

Way

Supervisory Patent Examine

ocnnology Center 2800